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Sommario/riassunto	The IEEE BiCMOS and Compound semiconductor Integrated Circuits and Technology Symposium (BCICTS) is the forum for developments in bipolar, BiCMOS, and compound semiconductor integrated circuits, devices, and technology Coverage includes all aspects of the technology, from materials, device fabrication, device phenomena, TCAD modeling, compact modeling, integrated circuit design, testing, and system applications A wide range of integrated circuit technologies are covered including bipolar, BiCMOS, SiGe, GaN, GaAs, InP, SiC, and CMOS The latest results in wireless, analog, RF, microwave, high speed digital, mixed signal, optoelectronic, millimeter wave, and THz integrated circuits are embraced.